

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/743,934	<b>Applicant(s)/Patent under Reexamination</b> PARK, JIN SU
	<b>Examiner</b> Anh Q. Tran	<b>Art Unit</b> 2819

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner